

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Docket No. 740756-2406		Serial No. Not Yet Assigned	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)							
				Applicant: Shunpei YAMAZAKI et al.			
				Filing Date: January 15, 2002		Group: 2815 2829	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
WAL	5,648,277	07/15/1997	Zhang et al.				
J	5,643,826	07/01/1997	Ohtani et al.				
	6,124,154	09/26/2000	Miyasaka				
WAL	5,550,070	08/27/1996	Funai et al.				
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes N	
WAL	08-078329	03/22/1996	Japan			Abstract	
J	07-321339	12/08/1995	Japan			Abstract	
	07-130652	05/19/1995	Japan			Abstract	
	07-135318	05/23/1995	Japan			Abstract	
WAL	05-109737	04/30/1993	Japan				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
WAL	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758						
Examiner	Date Considered			6/28/99			
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